

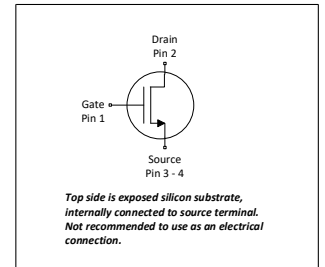
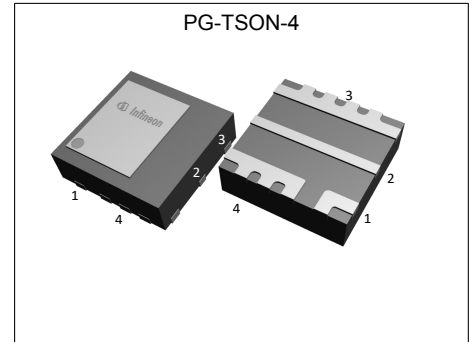
## CoolGaN™ Transistor 100 V G3

### Features

- Enhancement mode power transistor - normally OFF switch
- No reverse recovery charge
- Reverse conduction capability
- Low gate charge, low output charge
- Qualified according to JEDEC for target applications

### Potential applications

- Telecom AC/DC Synchronous Rectifiers
- Telecom DC/DC Synchronous Rectifiers
- Robotics
- Battery powered tool
- e-Mobility, UAVs
- Wireless charging
- ClassD Audio



**Table 1 Key Performance Parameters**

Parameter	Value	Unit
$V_{DS}$	100	V
$R_{DS(on),max}$	11	mΩ
$I_D$	24	A
$Q_{oss}$	14	nC
$Q_G$	3.4	nC
$Q_{rr}$	0	nC

Type / Ordering Code	Package	Marking	Related Links
IGB110S10S1	PG-TSON-4	BA1	-

## Table of Contents

Description .....	1
Maximum ratings .....	3
Thermal characteristics .....	3
Electrical characteristics .....	4
Electrical characteristics diagrams .....	6
Package Outlines .....	11
Revision History .....	12
Trademarks .....	12
Disclaimer .....	12

## 1 Maximum ratings

**Table 2 Maximum ratings**

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Continuous drain-source voltage	$V_{DS}$	-	-	100	V	$V_{GS}=0$ V
Pulsed drain-source voltage <sup>1)</sup>	$V_{DS, pulse}$	-	-	120	V	$V_{GS}=0$ V, 1 h total time
Continuous drain current	$I_D$	-	-	24 10	A	$V_{GS}=5$ V, $T_C=25$ °C $V_{GS}=5$ V, $T_A=25$ °C, $R_{THJA}=50$ °C/W <sup>2)</sup>
Pulsed drain current <sup>3)</sup>	$I_{D, pulse}$	-	-	80 40	A	$T_j=25$ °C $T_j=150$ °C
Gate-source voltage	$V_{GS}$	-4 -6.5	5 -	5.5 6.5	V	Continuous Pulsed
Power dissipation	$P_{tot}$	-	-	15 2.5	W	$T_C=25$ °C $T_A=25$ °C, $R_{THJA}=50$ °C/W
Storage temperature	$T_{stg}$	-55	-	150	°C	-
Operating temperature	$T_j$	-40	-	150	°C	-

## 2 Thermal characteristics

**Table 3 Thermal characteristics**

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Thermal resistance, junction - case, top	$R_{thJC(top)}$	-	1.4	1.7	°C/W	-
Thermal resistance, junction - case, bottom	$R_{thJC(bottom)}$	-	5.6	8.4	°C/W	-
Device on 1 layer PCB	$R_{thJA}$	-	71	80	°C/W	1s0p
Device on 4 layer PCB	$R_{thJA}$	-	50	-	°C/W	2s2p with vias

<sup>1)</sup> Provided as measure of robustness under abnormal operating conditions and not recommended for normal operation

<sup>2)</sup> Device on 4-layer FR4 PCB, vertical in still air.

<sup>3)</sup> Pulse current limited by transfer characteristic. See diagram 6.

### 3 Electrical characteristics

at  $T_j=25\text{ °C}$ , unless otherwise specified

**Table 4 Static characteristics**

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Gate threshold voltage <sup>1)</sup>	$V_{GS(th)}$	1.2	2.0	2.9	V	$V_{DS}=V_{GS}$ , $I_D=3\text{ mA}$ , measured within 5 ms after a pre-bias at $V_{GS}=5\text{ V}$ , $V_{DS}=0\text{ V}$ for at least 5 ms
Drain-source leakage current	$I_{DSS}$	-	0.1 20	10 250	$\mu\text{A}$	$V_{DS}=100\text{ V}$ , $V_{GS}=0\text{ V}$ , $T_j=25\text{ °C}$ $V_{DS}=100\text{ V}$ , $V_{GS}=0\text{ V}$ , $T_j=125\text{ °C}$
Gate-source leakage current	$I_{GSS}$	-	7.6 0.01 53 15	-	$\mu\text{A}$	$V_{GS}=5\text{ V}$ , $T_j=25\text{ °C}$ $V_{GS}=-4\text{ V}$ , $T_j=25\text{ °C}$ $V_{GS}=5\text{ V}$ , $T_j=125\text{ °C}$ $V_{GS}=-4\text{ V}$ , $T_j=125\text{ °C}$
Drain-source on-state resistance <sup>2)</sup>	$R_{DS(on)}$	-	8	11	$\text{m}\Omega$	$V_{GS}=5\text{ V}$ , $I_D=10\text{ A}$
Gate resistance <sup>3)</sup>	$R_G$	-	1.2	-	$\Omega$	-

**Table 5 Dynamic characteristics<sup>3)</sup>**

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Input capacitance	$C_{iss}$	-	390	-	pF	$V_{GS}=0\text{ V}$ , $V_{DS}=50\text{ V}$ , $f=1\text{ MHz}$
Output capacitance	$C_{oss}$	-	160	-	pF	$V_{GS}=0\text{ V}$ , $V_{DS}=50\text{ V}$ , $f=1\text{ MHz}$
Reverse transfer capacitance	$C_{rss}$	-	2.7	-	pF	$V_{GS}=0\text{ V}$ , $V_{DS}=50\text{ V}$ , $f=1\text{ MHz}$

**Table 6 Gate charge characteristics<sup>4)</sup>**

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Gate to source charge	$Q_{gs}$	-	1.1	-	nC	$V_{DD}=50\text{ V}$ , $I_D=10\text{ A}$ , $V_{GS}=0\text{ to }5\text{ V}$
Gate charge at threshold	$Q_{g(th)}$	-	0.8	-	nC	$V_{DD}=50\text{ V}$ , $I_D=10\text{ A}$ , $V_{GS}=0\text{ to }5\text{ V}$
Gate to drain charge <sup>3)</sup>	$Q_{gd}$	-	0.7	-	nC	$V_{DD}=50\text{ V}$ , $I_D=10\text{ A}$ , $V_{GS}=0\text{ to }5\text{ V}$
Switching charge	$Q_{sw}$	-	1.0	-	nC	$V_{DD}=50\text{ V}$ , $I_D=10\text{ A}$ , $V_{GS}=0\text{ to }5\text{ V}$
Gate charge total <sup>3)</sup>	$Q_g$	-	3.4	-	nC	$V_{DD}=50\text{ V}$ , $I_D=10\text{ A}$ , $V_{GS}=0\text{ to }5\text{ V}$
Gate plateau voltage	$V_{plateau}$	-	2.7	-	V	$V_{DD}=50\text{ V}$ , $I_D=10\text{ A}$ , $V_{GS}=0\text{ to }5\text{ V}$
Output charge <sup>3)</sup>	$Q_{oss}$	-	14	-	nC	$V_{DD}=50\text{ V}$ , $V_{GS}=0\text{ V}$

<sup>1)</sup> When tested without the specified  $V_{GS}$  pre-bias,  $V_{GS(th)}$  will typically be 0.7 V lower than the threshold voltage measured under the specified conditions.

<sup>2)</sup>  $R_{DS(ON)}$  is measured without prior drain bias or switching stress. An upcoming application note will provide detailed information about dynamic  $R_{DS(ON)}$  and recommendations for *in situ* measurement in target application conditions.

<sup>3)</sup> Defined by design. Not subject to production test.

<sup>4)</sup> See "Gate charge waveforms" for parameter definition

**Table 7 Reverse operation**

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Reverse continuous current	$I_S$	-	-	4	A	$T_C=25\text{ °C}$
Pulsed current, reverse	$I_{S,pulse}$	-	-	80	A	$T_C=25\text{ °C}$
Source-Drain reverse voltage	$V_{SD}$	-	2.5	3.4	V	$V_{GS}=0\text{ V}$ , $I_{S,pulse}=10\text{ A}$ , $T_j=25\text{ °C}$
Reverse recovery charge <sup>1)</sup>	$Q_{rr}$	-	0	-	nC	$V_R=50\text{ V}$ , $I_{S,pulse}=10\text{ A}$ , $di_{S,pulse}/dt=100\text{ A}/\mu\text{s}$

<sup>1)</sup> Defined by design. Not subject to production test.

### 4 Electrical characteristics diagrams

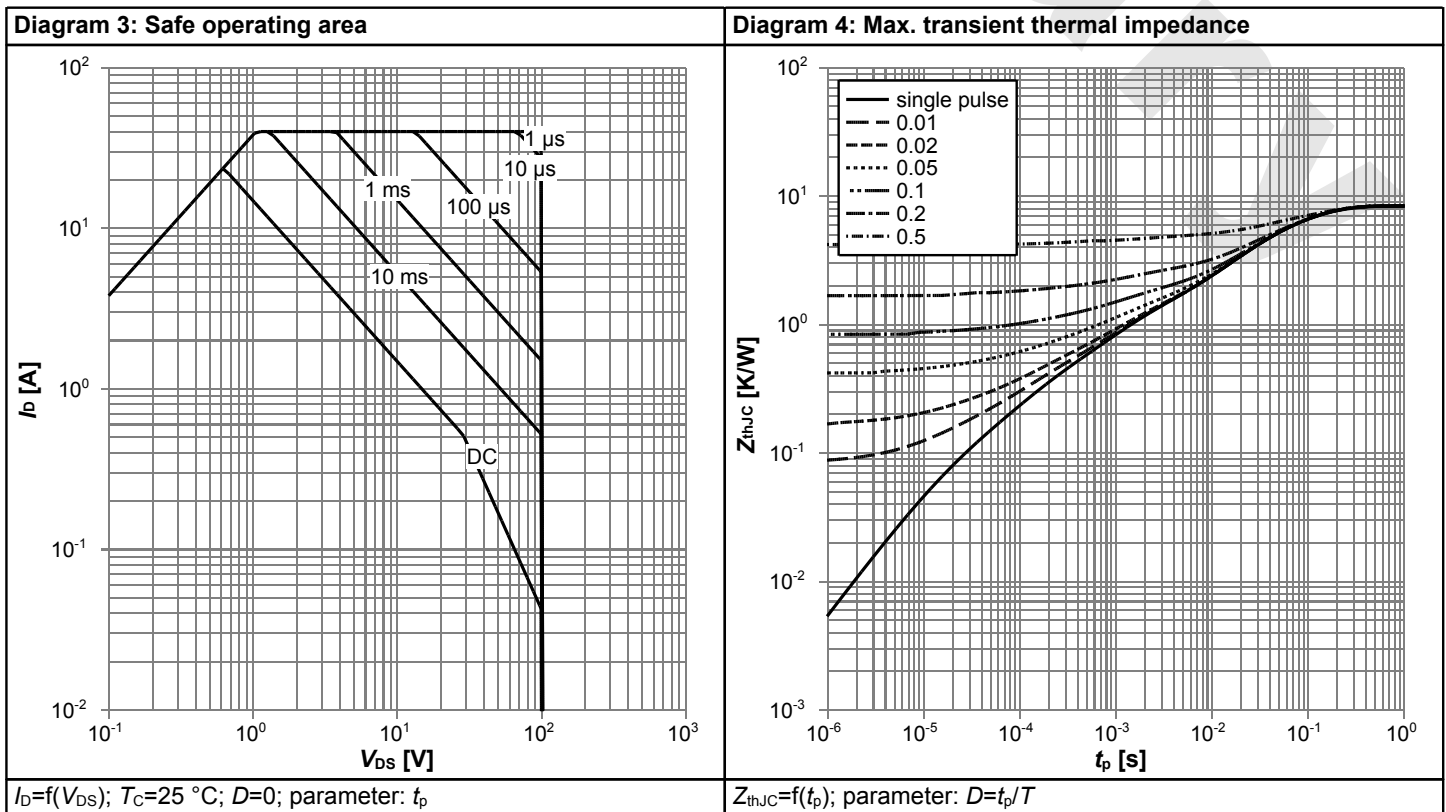
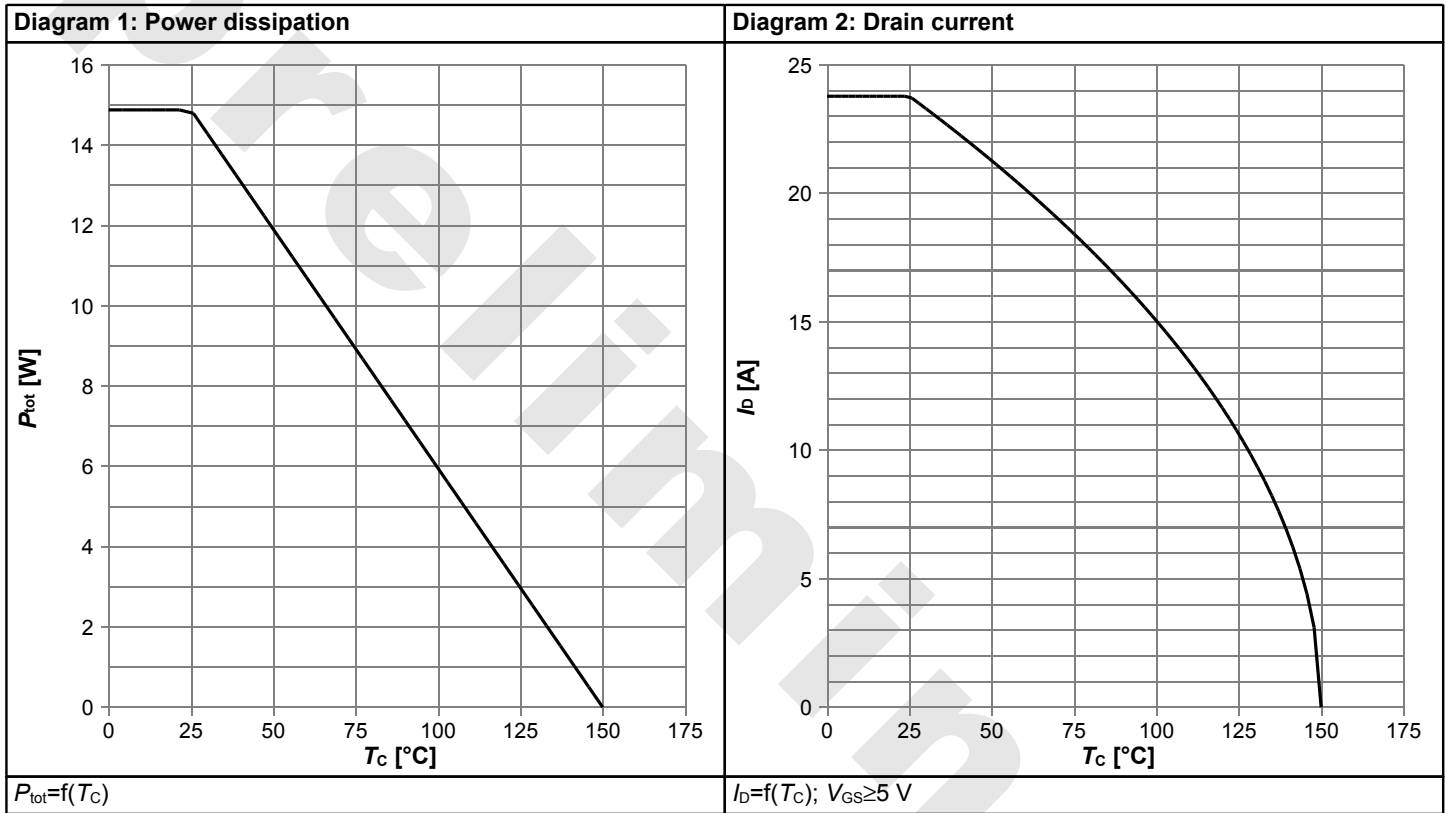
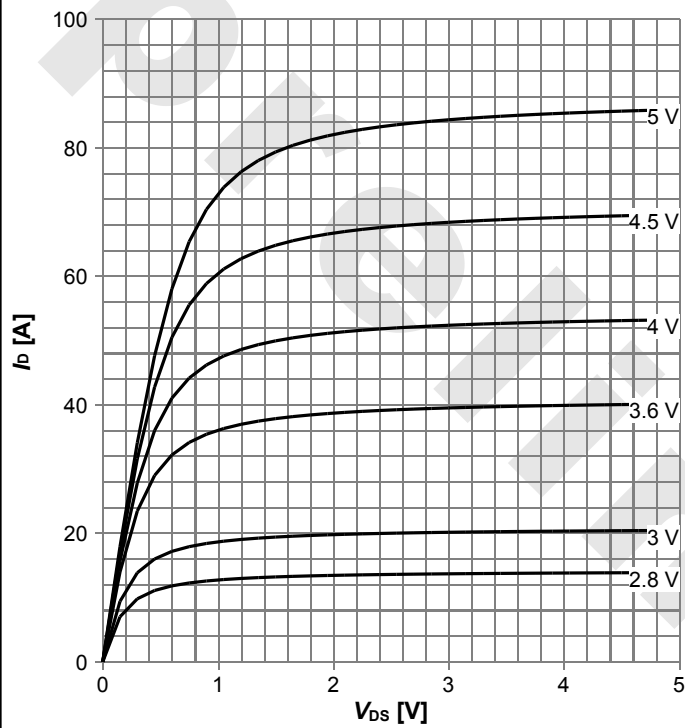
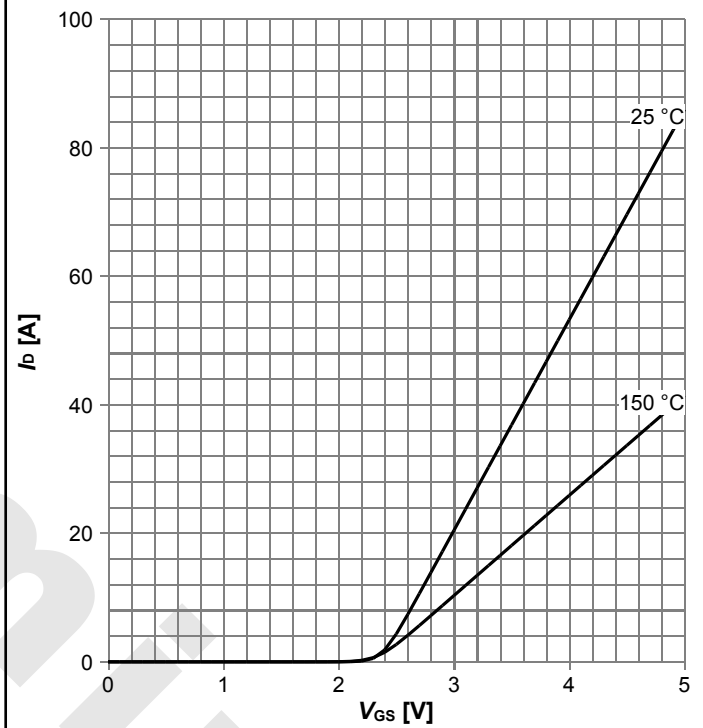


Diagram 5: Typ. output characteristics



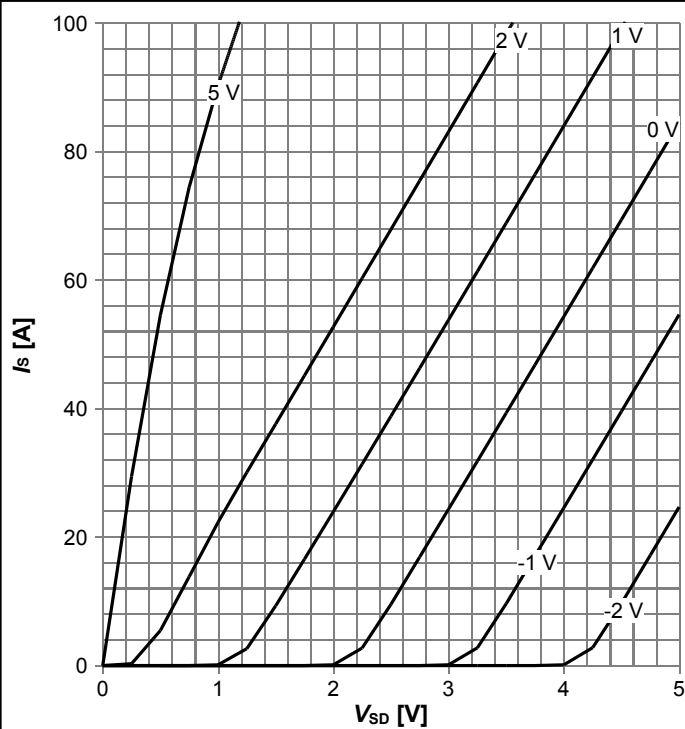
$I_D = f(V_{DS})$ ,  $T_j = 25\text{ °C}$ ; parameter:  $V_{GS}$

Diagram 6: Typ. transfer characteristics



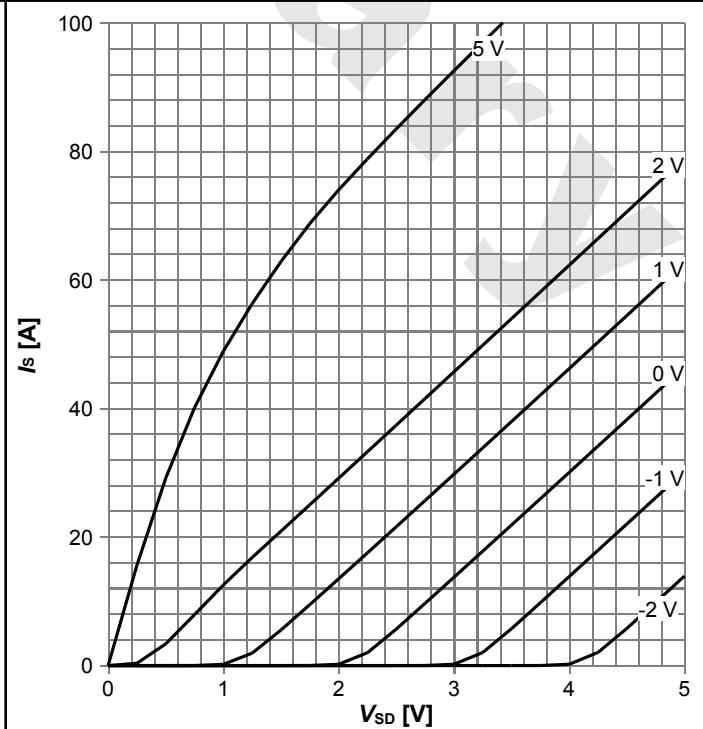
$I_D = f(V_{GS})$ ,  $|V_{DS}| > 2|I_D|R_{DS(on)max}$ ; parameter:  $T_j$

Diagram 7: Typ. reverse output characteristics



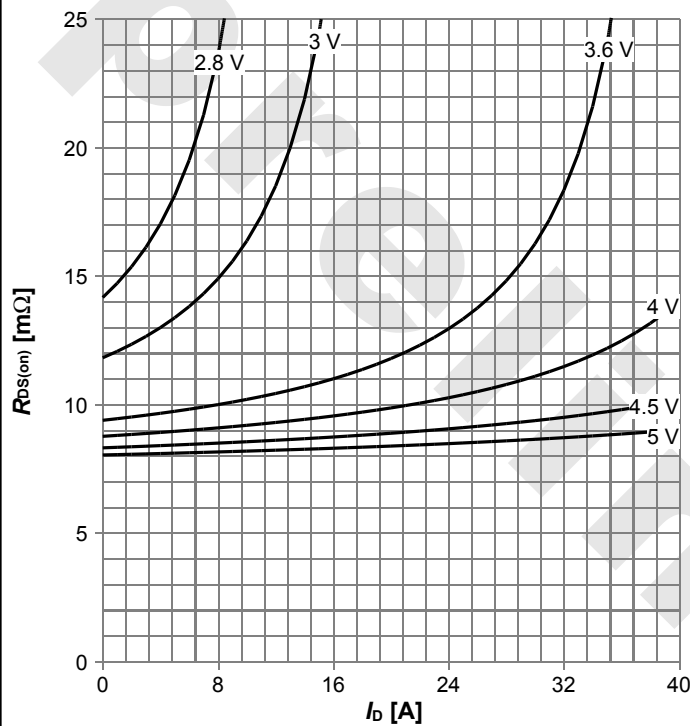
$I_F = f(V_{SD})$ ,  $T_j = 25\text{ °C}$ ; parameter:  $V_{GS}$

Diagram 8: Typ. reverse output characteristics



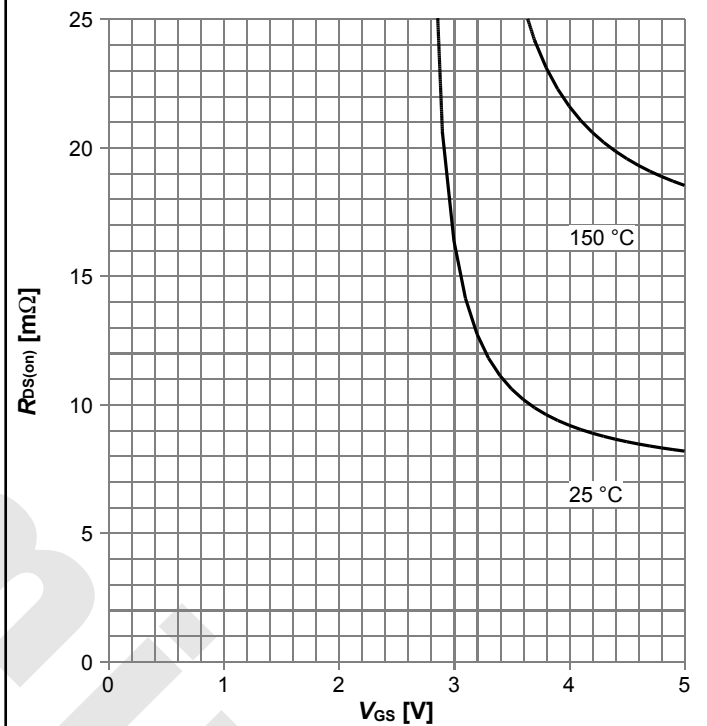
$I_F = f(V_{SD})$ ,  $T_j = 125\text{ °C}$ ; parameter:  $V_{GS}$

Diagram 9: Typ. drain-source on resistance



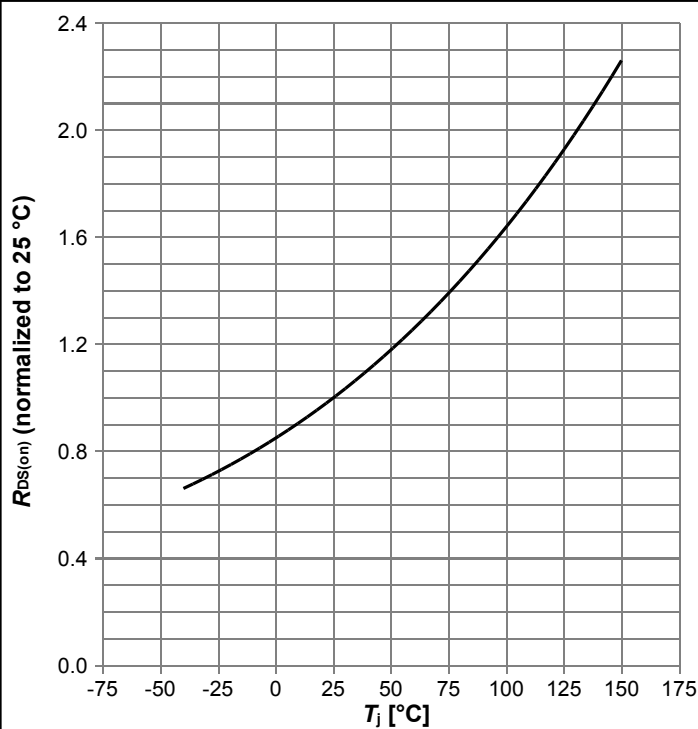
$R_{DS(on)}=f(I_D)$ ,  $T_j=25\text{ }^\circ\text{C}$ ; parameter:  $V_{GS}$

Diagram 10: Typ. drain-source on resistance



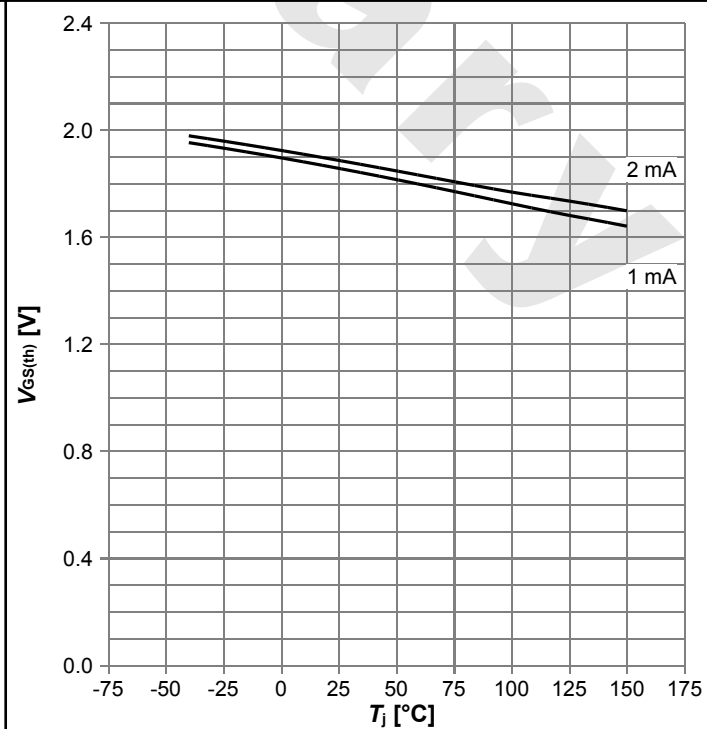
$R_{DS(on)}=f(V_{GS})$ ,  $I_D=10\text{ A}$ ; parameter:  $T_j$

Diagram 11: Normalized drain-source on resistance



$R_{DS(on)}=f(T_j)$ ,  $I_D=10\text{ A}$ ,  $V_{GS}=5\text{ V}$

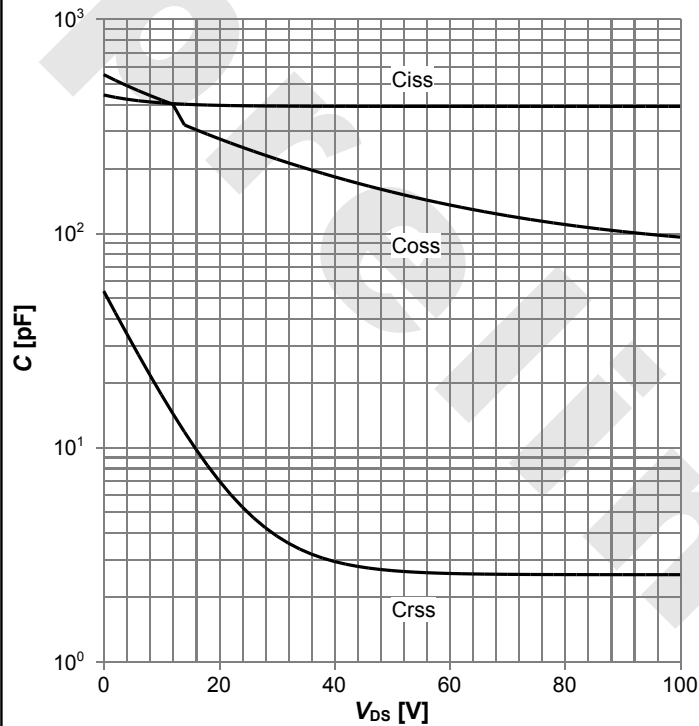
Diagram 12: Typ. gate threshold voltage



$V_{GS(th)}=f(T_j)$ ,  $V_{GS}=V_{DS}$ ; parameter:  $I_D$

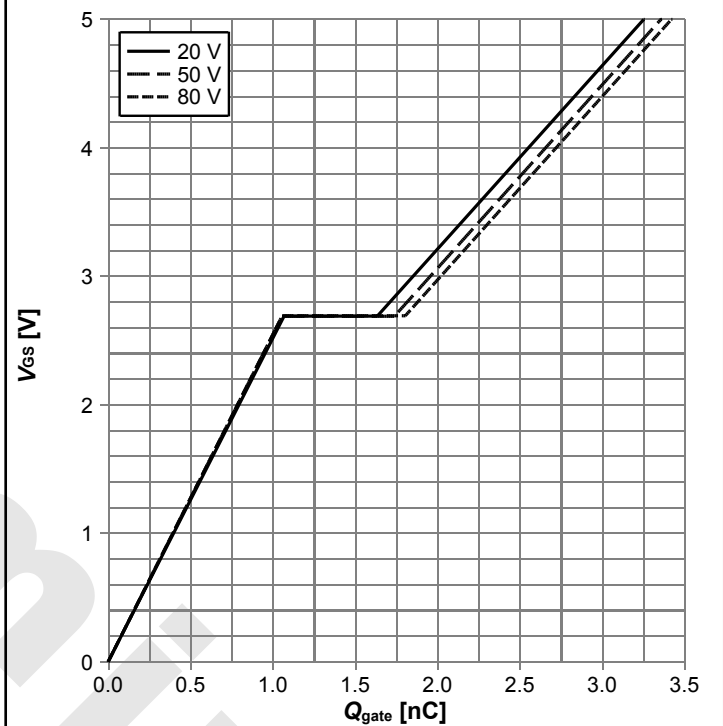


Diagram 13: Typ. capacitances



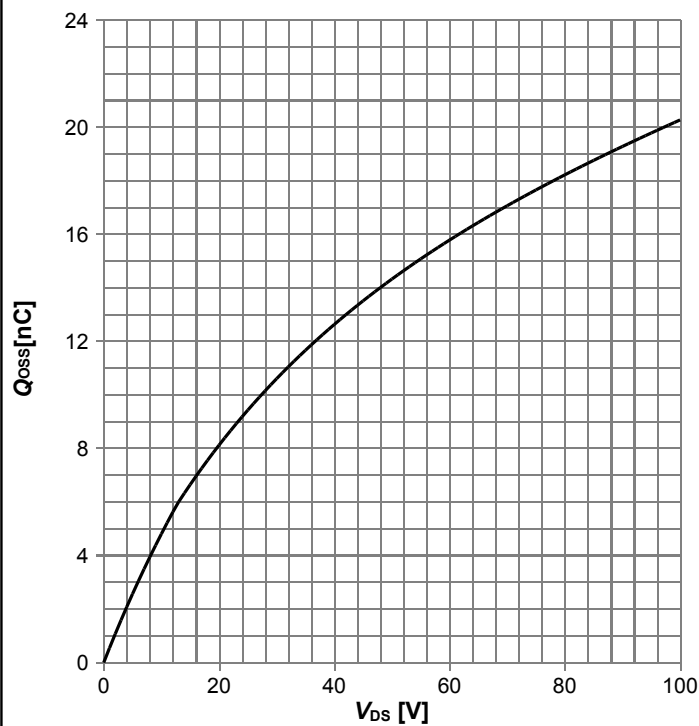
$C=f(V_{DS}); V_{GS}=0\text{ V}; f=1\text{ MHz}$

Diagram 14: Typ. gate charge



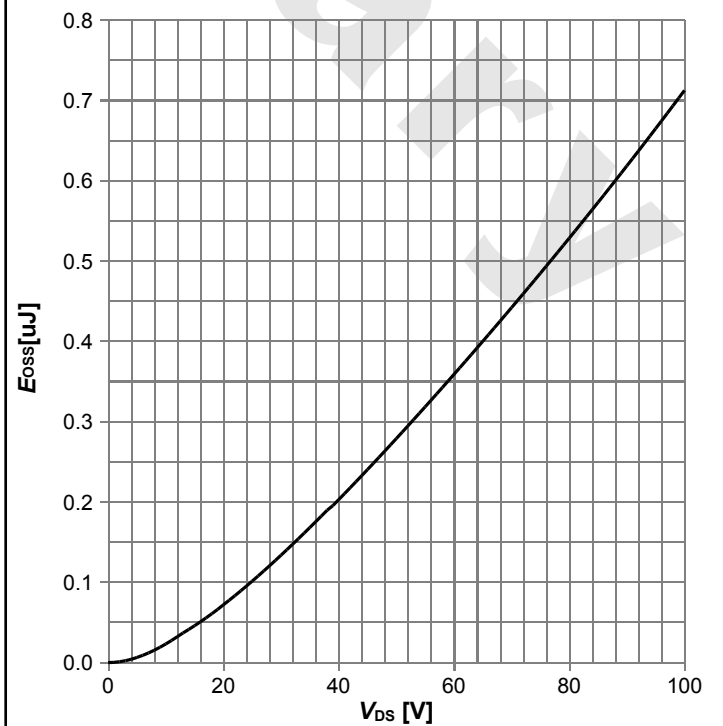
$V_{GS}=f(Q_{gate}), I_D=10\text{ A pulsed}, T_j=25\text{ °C}; \text{parameter: } V_{DD}$

Diagram 15: Typ output charge



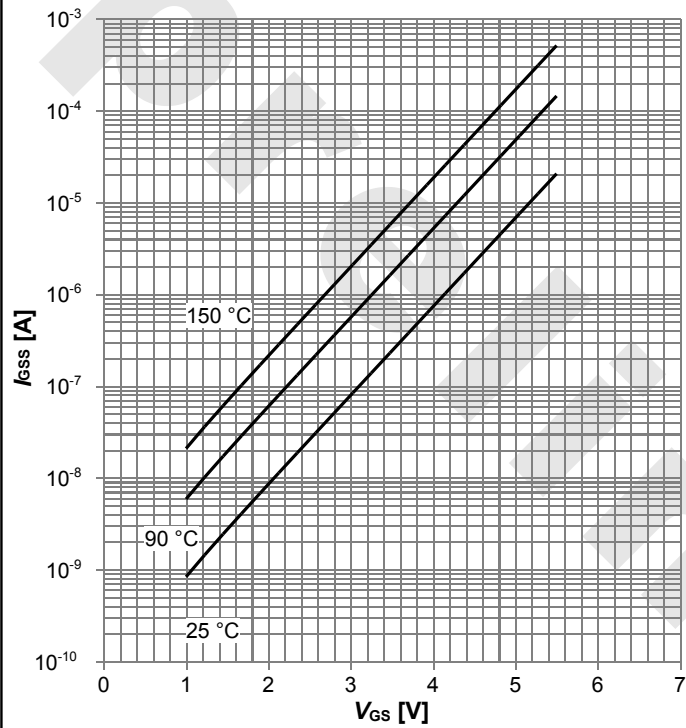
$Q_{oss}=f(V_{DS}), V_{GS}=0\text{ V}$

Diagram 16: Typ output energy



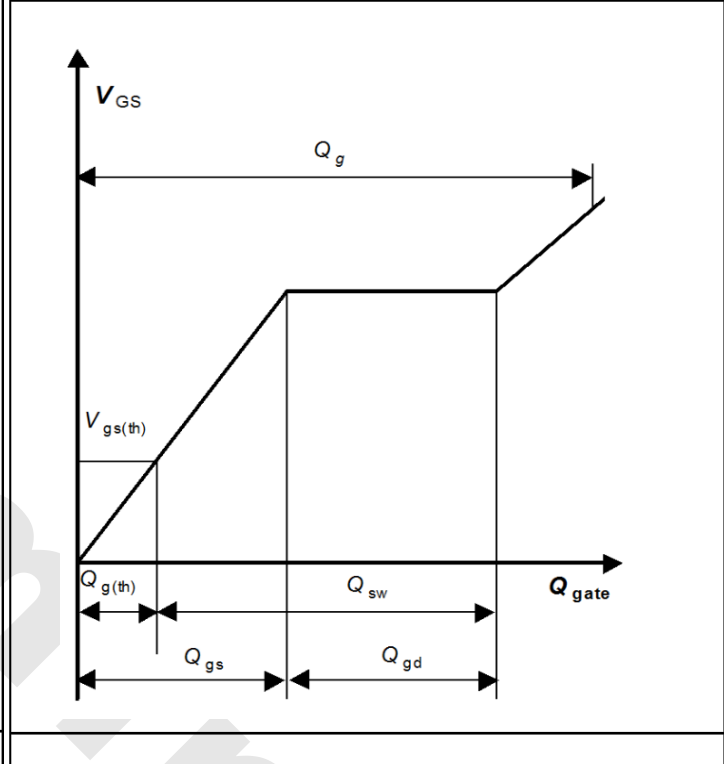
$E_{oss}=f(V_{DS}), V_{GS}=0\text{ V}$

Diagram 17: Typ gate-source leakage current

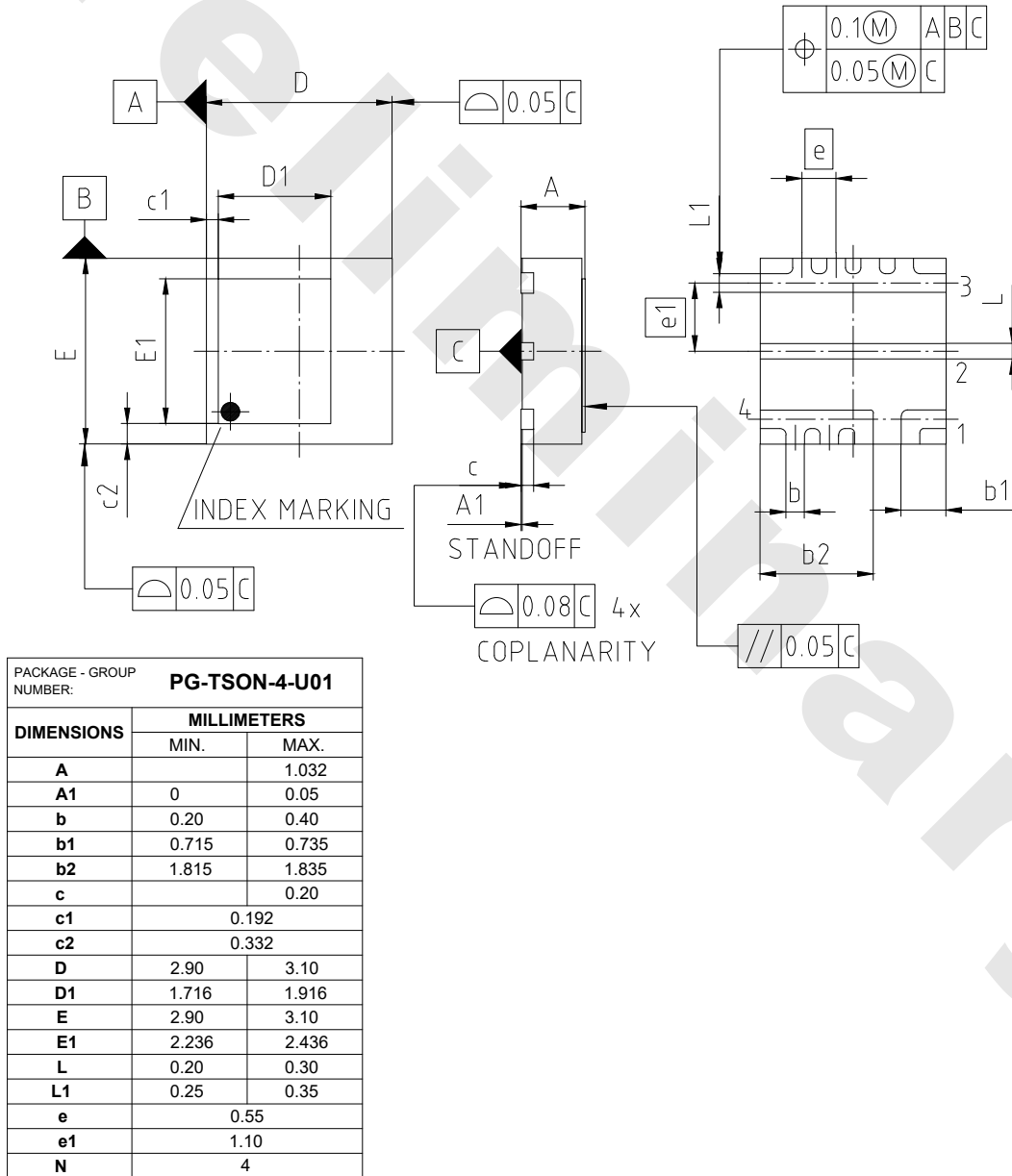


$I_{GSS}=f(V_{GS}), V_{DS}=0\text{ V}; \text{parameter: } T_j$

Diagram Gate charge waveforms



## 5 Package Outlines



NOTE:  
DIMENSIONS DO NOT INCLUDE MOLD FLASH, PROTRUSION OR GATE BURRS

Figure 1 Outline PG-TSON-4, dimensions in mm

## Revision History

IGB110S10S1

**Revision: 2024-05-20, Rev. 0.9**

Previous Revision

Revision	Date	Subjects (major changes since last revision)
0.9	-	Release of preliminary version

### Trademarks

All referenced product or service names and trademarks are the property of their respective owners.

### We Listen to Your Comments

Any information within this document that you feel is wrong, unclear or missing at all? Your feedback will help us to continuously improve the quality of this document. Please send your proposal (including a reference to this document) to:

[erratum@infineon.com](mailto:erratum@infineon.com)

### Published by

**Infineon Technologies AG**  
81726 München, Germany  
© 2024 Infineon Technologies AG  
All Rights Reserved.

### Legal Disclaimer

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics ("Beschaffenheitsgarantie").

With respect to any examples, hints or any typical values stated herein and/or any information regarding the application of the product, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation warranties of non-infringement of intellectual property rights of any third party.

In addition, any information given in this document is subject to customer's compliance with its obligations stated in this document and any applicable legal requirements, norms and standards concerning customer's products and any use of the product of Infineon Technologies in customer's applications.

The data contained in this document is exclusively intended for technically trained staff. It is the responsibility of customer's technical departments to evaluate the suitability of the product for the intended application and the completeness of the product information given in this document with respect to such application.

### Information

For further information on technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies Office ([www.infineon.com](http://www.infineon.com)).

### Warnings

Due to technical requirements, components may contain dangerous substances. For information on the types in question, please contact the nearest Infineon Technologies Office.

The Infineon Technologies component described in this Data Sheet may be used in life-support devices or systems and/or automotive, aviation and aerospace applications or systems only with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support, automotive, aviation and aerospace device or system or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.